

## N-Channel Enhancement Mode MOSFET

Primary characteristics			
Symbol	Parameter	Value	Unit
$I_D$	Continuous drain current ( $T_A=25^\circ\text{C}$ )	33	A
$V_{DSS}$	Drain source voltage	100	V
$R_{DS(on)}$	Static drain-source on-resistance	2.2	$\text{m}\Omega$ MAX

Case dimensions								
A	L	H	M	N	E	F	G	P
K	B	I	D	O	J	C		
TOLL								
	A	B	C	D	E	F	G	H
TYP	9.9	10.4	2.3	0.7	0.6	0.75	1.2	0.7
MIN	9.7	10.2	2.1	0.6	0.5	0.65	1.1	0.6
MAX	10.1	10.6	2.5	0.8	0.7	0.85	1.3	0.8
	I	J	K	L	M	N	O	P
TYP	0.65	0.50	11.7	9.8	0.6	3.3	0.35	9.2
MIN	0.55	0.45	11.5	9.6	0.5	3.1	0.25	9.0
MAX	0.75	0.55	11.9	10.0	0.7	3.5	0.45	9.4
All measurements in mm								

Maximum ratings ( $T_A = 25^\circ\text{C}$ unless otherwise noted)				
Characteristic		Symbol	Value	Unit
Drain-source voltage		$V_{DSS}$	100	V
Gate-source voltage		$V_{GSS}$	$\pm 20$	V
Continuous drain current	$T_C=25^\circ\text{C}$	$I_D$	300	A
	$T_C=100^\circ\text{C}$		210	A
	$T_A=25^\circ\text{C}^1)$		33	A
	$T_A=100^\circ\text{C}^1)$		23	A
Pulsed drain current ( $t_p=10\mu\text{s}$ , $T_C=25^\circ\text{C}$ )		$I_{DM}$	1200	A
Thermal resistance junction-to-case		$R_{ejC}$	0.5 (0.4 typ.)	$^\circ\text{C}/\text{W}$
Thermal resistance junction-to-air <sup>1)</sup>		$R_{ejA}$	40 (24 typ.)	$^\circ\text{C}/\text{W}$
Single pulse avalanche energy <sup>3)</sup>		$E_{AS}$	3500	mJ
Power Dissipation ( $T_C=25^\circ\text{C}$ )		$P_D$	300	W
Operating junction temperature range		$T_J$ , $T_{STG}$	-55 ~ 175	$^\circ\text{C}$

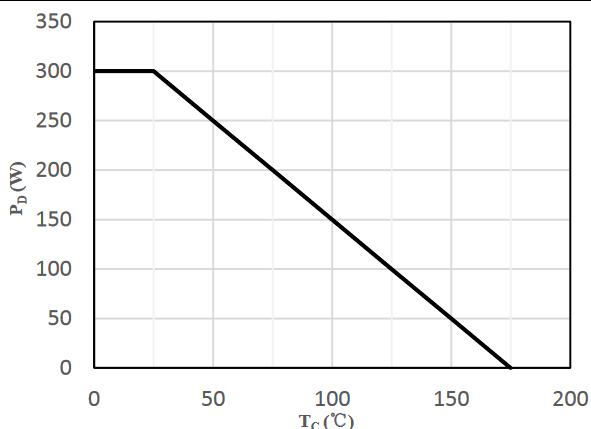
Electrical characteristics ( $T_A = 25^\circ\text{C}$ )						
Characteristic	Test condition	Symbol	Min.	Value Typ.	Max.	Unit
Drain-source breakdown voltage	$V_{GS}=0\text{V}, I_D=1.0\text{mA}$	$V_{DSS}$	100	-	-	V
Zero gate voltage drain current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$	$I_{DSS}$	-	-	5.0	$\mu\text{A}$
Gate body leakage current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	$I_{GSS}$	-	-	$\pm 100$	nA
Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	$V_{GS(\text{TH})}$	2.0	3.0	4.0	V
Static drain-source on-state resistance <sup>2)</sup>	$V_{GS}=10\text{V}, I_D=150\text{A}$	$R_{DS(\text{ON})}$	-	1.3	1.6	$\text{m}\Omega$
	$V_{GS}=6.0\text{V}, I_D=75\text{A}$		-	1.7	2.2	
Gate resistance	$V_{GS}=0\text{V}, f=1.0\text{MHz}$	$R_G$	-	2.0	-	$\Omega$
Dynamic electrical characteristics						
Characteristic	Test condition	Symbol	Min.	Value Typ.	Max.	Unit
Input capacitance	$V_{DS}=50\text{V}$ $V_{GS}=0\text{V}$ $f=1.0\text{MHz}$	$C_{ISS}$	-	13113	-	$\text{pF}$
Output capacitance		$C_{OSS}$	-	2167	-	
Reverse transfer capacitance		$C_{RSS}$	-	25	-	
Switching characteristics						
Characteristic	Test condition	Symbol	Min.	Value Typ.	Max.	Unit
Turn ON delay time <sup>4)</sup>	$V_{DD}=50\text{V}$ $V_{GS}=10\text{V}$ $I_D=100\text{A}$ $R_G=1.8\Omega$	$t_{d(\text{ON})}$	-	20	-	ns
Turn ON rise time <sup>4)</sup>		$t_r$	-	13	-	
Turn OFF delay time <sup>4)</sup>		$t_{d(\text{OFF})}$	-	49	-	
Turn OFF fall time <sup>4)</sup>		$t_f$	-	17	-	
Total gate-charge	$V_{DD}=50\text{V}$ $V_{GS}=10\text{V}$ $I_D=100\text{A}$	$Q_G$	-	211	-	nC
Gate to source charge		$Q_{GS}$	-	57	-	
Gate to drain (Miller) charge		$Q_{GD}$	-	59	-	
Source-drain diode characteristics						
Characteristic	Test condition	Symbol	Min.	Value Typ.	Max.	Unit
Diode forward voltage <sup>2)</sup>	$I_S=100\text{A}, V_{GS}=0\text{V}$	$V_{SD}$	-	0.8	1.2	V
Reverse recovery time	$I_F=40\text{A}, V_{GS}=0\text{V}$ $dI/dt=100\text{A}/\mu\text{s}$	$t_{rr}$	-	118	-	ns
Reverse recovery charge		$Q_{rr}$	-	346	-	nC

Notes:

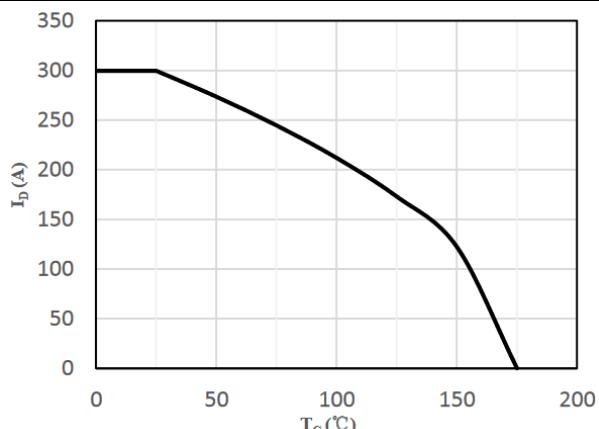
- 1) The data tested when surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper
- 2) The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
- 3) The Es data shows max. rating. The test condition is  $V_{DD}=80\text{V}, V_{GS}=10\text{V}, L=50\text{mH}$
- 4) Guaranteed by design, not subject to production

### Typical characteristics

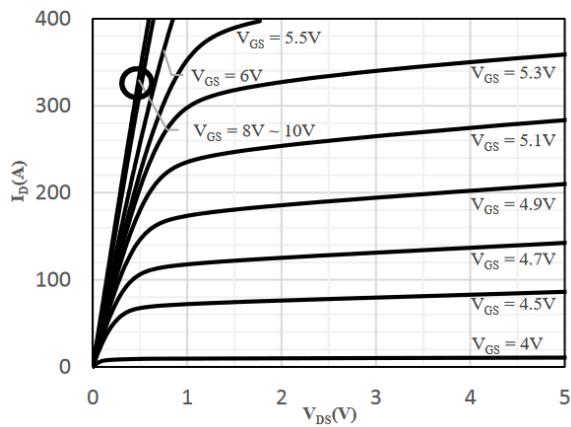
#### Power dissipation



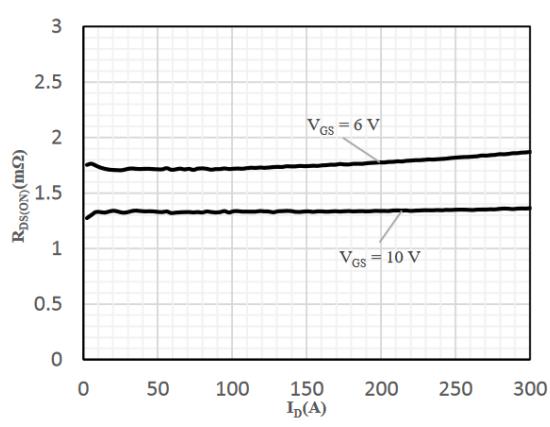
#### Drain current



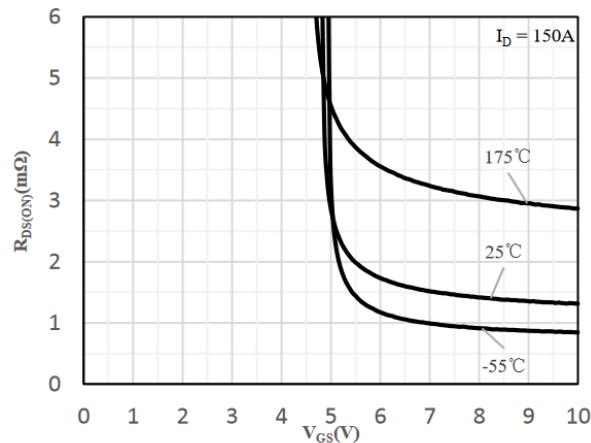
#### Typical output characteristics



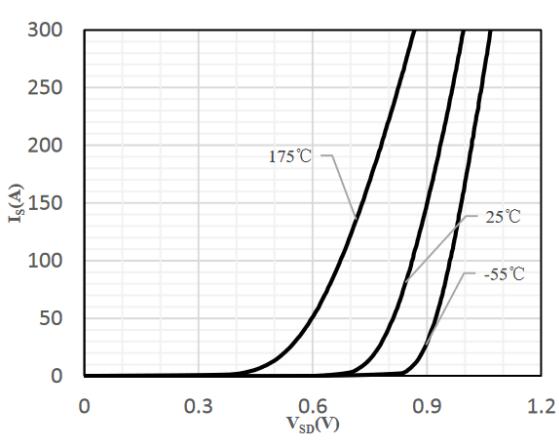
#### ON resistance vs. drain current and gate voltage



#### ON resistance vs. gate-source voltage

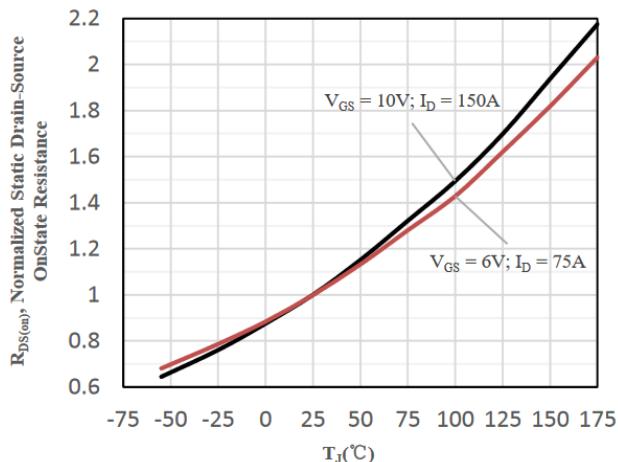


#### Body-diode characteristics

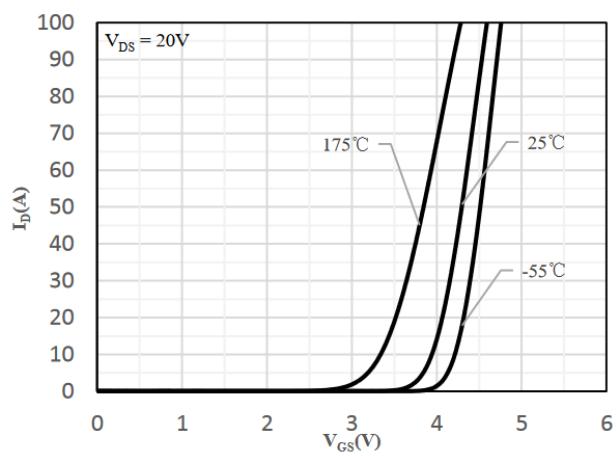


### Typical characteristics

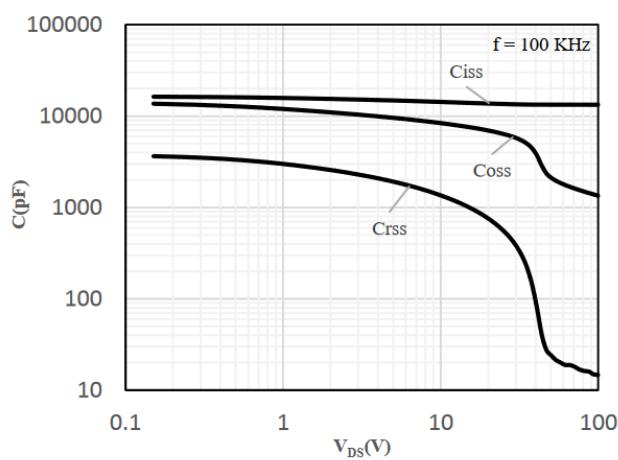
#### Normalized ON resistance vs. junction temperature



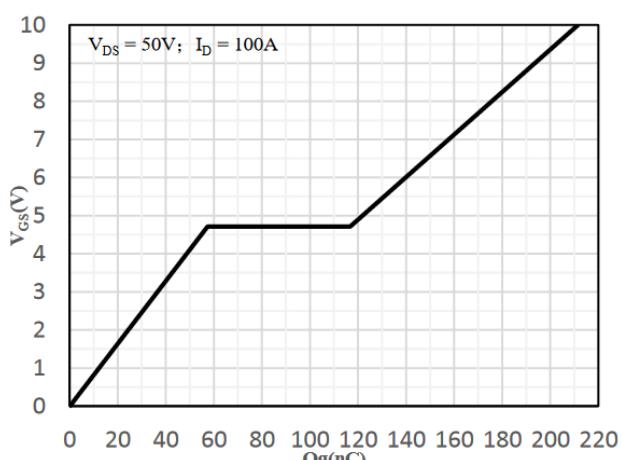
#### Transfer characteristics



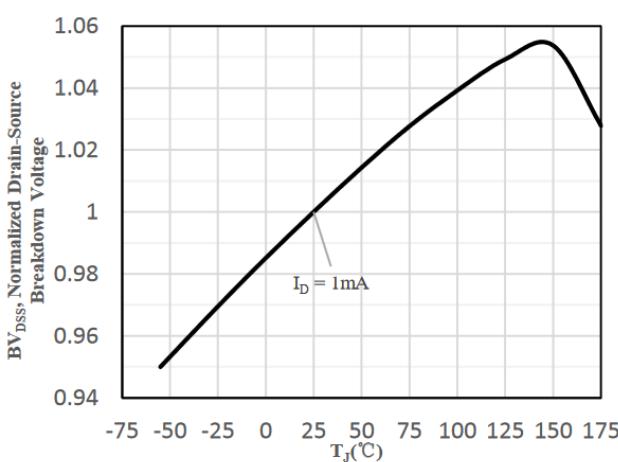
#### Capacitance characteristics



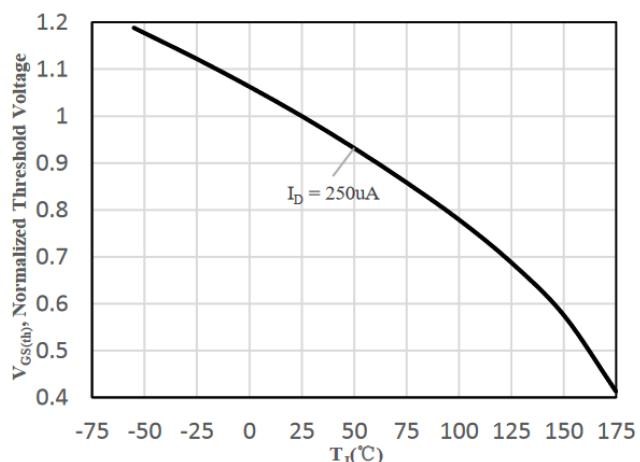
#### Gate charge characteristics

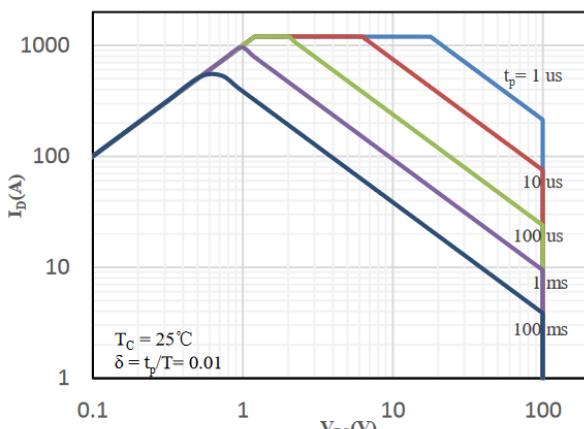
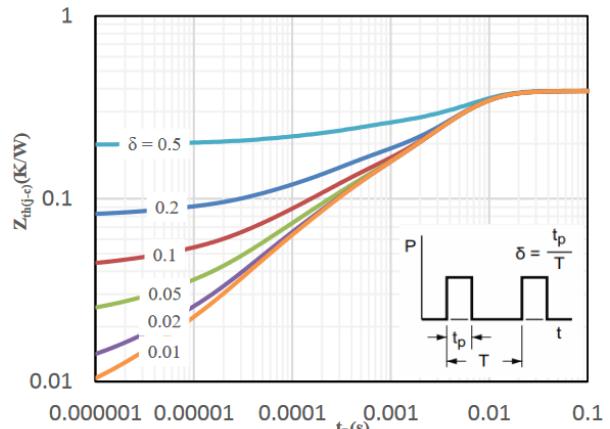
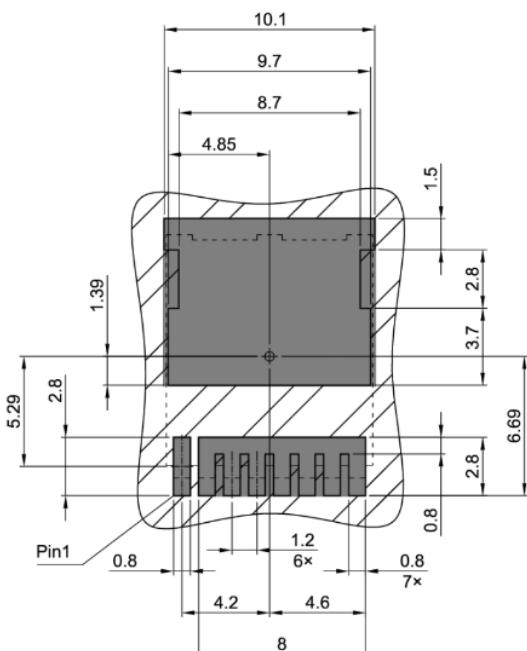


#### Normalized breakdown voltage vs. junction temperature



#### Normalized $V_{GS(TH)}$ vs. junction temperature



**Typical characteristics**
**Safe operating area**

**Maximum transient thermal impedance**

**Suggested soldering pad layout**

**TOLL**

**Ordering information**

Part Number	Marking	Package	Shipping Quantity	Dimensions
AKS016N10TH-TL	016N10TH	TOLL	2000 pcs / tape & reel	---

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